Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10029394	KIM ET AL.
Examiner	Art Unit
Nauven, Khiem D	2823

	SEARCHED	ARCHED	
Class	Subclass	Date	Examiner
438	151, 197, 201, 257, 261, 288, FOR431	10/25/2007	KN
257	314, 315, E29.129, E29.3, E21.422, E21.68, E21.687, E21.688	10/25/2007	KN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search updated (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	10/25/2007	KN
EAST text search updated (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	9/27/2008	/KN/

	INTERFERENCE SEARCH		
Class	Subclass	Date	Examiner

/KHIEM D NGUYEN/ Examiner.Art Unit 2823	

U.S. Patent and Trademark Office Part of Paper No.: 20080928